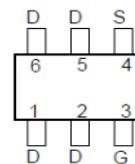
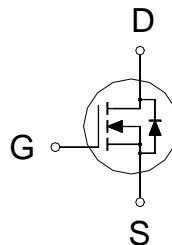


NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****PA520BA**
SOT-23-6
Halogen-Free & Lead-Free**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
30V	20mΩ	6A



G: GATE
D: DRAIN
S: SOURCE

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	6	A
		4.7	
Pulsed Drain Current ¹	I_{DM}	30	
Avalanche Current	I_{AS}	17	
Avalanche Energy	E_{AS}	15	mJ
Power Dissipation	P_D	1.1	W
		0.7	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATING

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	40	110	°C / W
Junction-to-Ambient ²	$R_{\theta JA}$			

¹Pulse width limited by maximum junction temperature.

²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$.

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	30			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.4	2.5	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 24\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 10\text{V}, I_D = 6\text{A}$		15.3	20	$\text{m}\Omega$
		$V_{GS} = 4.5\text{V}, I_D = 6\text{A}$		18.2	25	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5\text{V}, I_D = 6\text{A}$		41		S

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DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$		496		pF
Output Capacitance	C_{oss}			81		
Reverse Transfer Capacitance	C_{rss}			73		
Total Gate Charge ²	$Q_{g(V_{GS}=10V)}$	$V_{DS} = 15V, I_D = 6A$		14.4		nC
	$Q_{g(V_{GS}=4.5V)}$			8		
Gate-Source Charge ²	Q_{gs}			1.6		
Gate-Drain Charge ²	Q_{gd}			3.9		
Turn-On Delay Time ²	$t_{d(on)}$			12		
Rise Time ²	t_r	$V_{DD} = 15V,$ $I_D \approx 6A, V_{GS} = 10V, R_{GEN} = 6\Omega$		10		nS
Turn-Off Delay Time ²	$t_{d(off)}$			27		
Fall Time ²	t_f			10		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current ²	I_S			6		A
Forward Voltage ¹	V_{SD}	$I_F = 6A, V_{GS} = 0V$		1		V
Reverse Recovery Time	t_{rr}	$I_F = 6A, dI_F/dt = 100A / \mu S$ $V_{GS} = 0V$		10.7		nS
Reverse Recovery Charge	Q_{rr}			2.6		nC

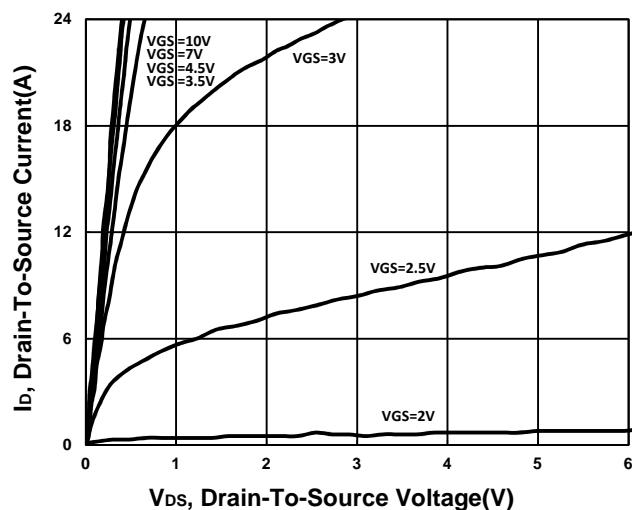
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

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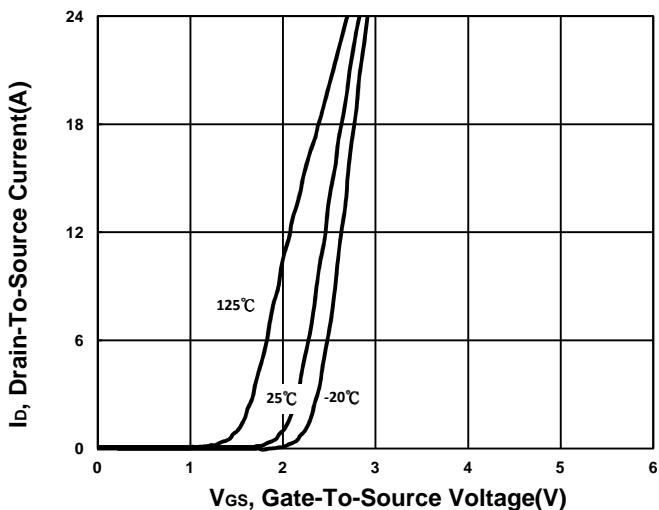
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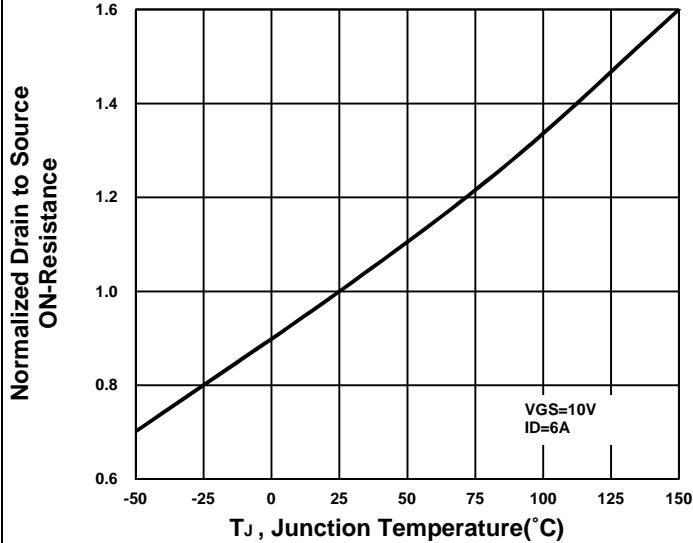
Output Characteristics



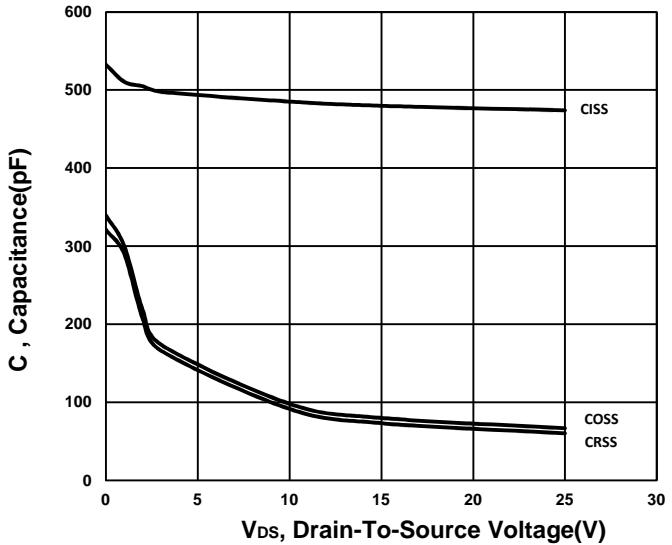
Transfer Characteristics



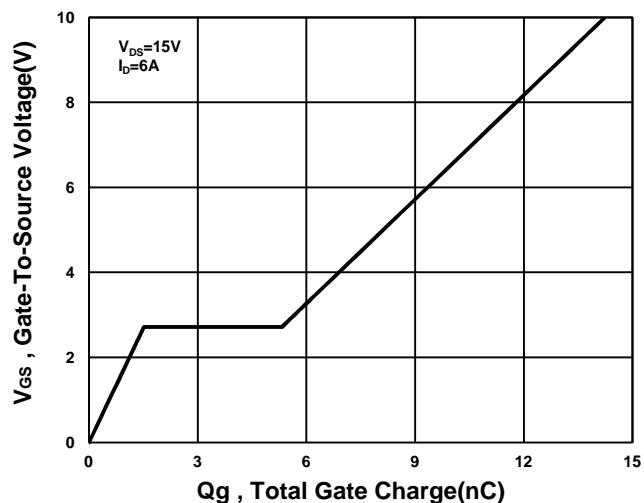
On-Resistance VS Temperature



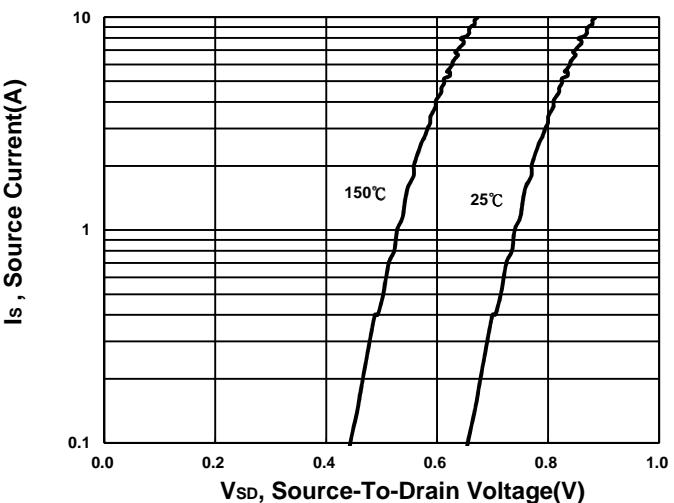
Capacitance Characteristic



Gate charge Characteristics



Source-Drain Diode Forward Voltage



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